

Low resistance measurements - Methods and guidance

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN IEC 62812:2019 sisaldab Euroopa standardi EN IEC 62812:2019 ingliskeelset teksti.	This Estonian standard EVS-EN IEC 62812:2019 consists of the English text of the European standard EN IEC 62812:2019.
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English Version

Low resistance measurements - Methods and guidance
(IEC 62812:2019)

Mesures de faibles résistances - Méthodes et
recommandations
(IEC 62812:2019)

Messung niederohmiger Widerstände - Verfahren und
Leitfaden
(IEC 62812:2019)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 40/2665/FDIS, future edition 1 of IEC 62812, prepared by IEC/TC 40 "Capacitors and resistors for electronic equipment" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 62812:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2020-03-06
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2022-06-06

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60115-2	NOTE	Harmonized as EN 60115-2
IEC 60115-8	NOTE	Harmonized as EN 60115-8
IEC 60301	NOTE	Harmonized as EN 60301
IEC 61249-5-1	NOTE	Harmonized as EN 61249-5-1

Annex ZA

(normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	-	Environmental testing - Part 1: General and guidance	EN 60068-1	-
IEC 60115-1 (mod)	2008	Fixed resistors for use in electronic equipment - Part 1: Generic specification	EN 60115-1	2011
-	-		+ A11	2015
IEC 60294	-	Measurement of the dimensions of a cylindrical component with axial terminations	EN 60294	-

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

LOW RESISTANCE MEASUREMENTS – METHODS AND GUIDANCE

FOREWORD

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International Standard IEC 62812 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
40/2665/FDIS	40/2671/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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